Features

- Fast Read Access Time 45 ns
- Low Power CMOS Operation
 - 100 µA max. Standby
 - 30 mA max. Active at 5 MHz
- JEDEC Standard Packages
 - 44-Lead PLCC
 - 40-Lead VSOP (10mm x 14mm)
- 5V \pm 10% Power Supply
- High Reliability CMOS Technology
 - 2000V ESD Protection
 - 200 mA Latchup Immunity
- Rapid[™] Programming Algorithm 50 µs/word (typical)
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Commercial and Industrial Temperature Ranges

Description

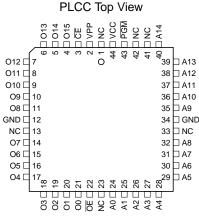
The AT27C516 is a low-power, high performance 524,288-bit one-time programmable read only memory (OTP EPROM) organized 32K by 16 bits. It requires only one 5V power supply in normal read mode operation. Any word can be accessed in less than 45 ns, eliminating the need for speed reducing WAIT states. The by-16 organization make this part ideal for high-performance 16- and 32-bit microprocessor systems.

In read mode, the AT27C516 typically consumes 15 mA. Standby mode supply current is typically less than 10 $\mu A.$ (continued)

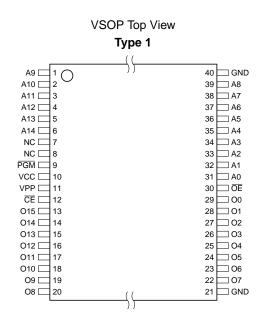
Pin Configurations

| Function |
|----------------|
| Addresses |
| Outputs |
| Chip Enable |
| Output Enable |
| Program Strobe |
| No Connect |
| |

Note: Both GND pins must be connected.



Note: PLCC Package Pins 1 and 23 are DON'T CONNECT.





512K (32K x 16) OTP EPROM

AT27C516

Rev. 0362C-10/98





The AT27C516 is available in industry standard JEDECapproved one-time programmable (OTP) plastic PLCC and VSOP packages. The device features two-line control (\overline{CE} , \overline{OE}) to eliminate bus contention in high-speed systems.

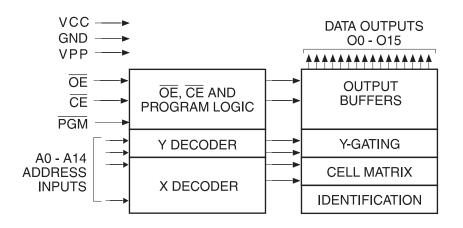
With 32K word storage capability, the AT27C516 allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

Atmel's 27C516 have additional features to ensure high quality and efficient production use. The RapidTM Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 50 μ s/word. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.

Block Diagram

System Considerations

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed data sheet limits, resulting in device non-conformance. At a minimum, a 0.1 μ F high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7 μ F bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.



Absolute Maximum Ratings*

| Temperature Under Bias |
|---|
| Storage Temperature65°C to +150°C |
| Voltage on Any Pin with Respect to Ground2.0V to +7.0V ⁽¹⁾ |
| Voltage on A9 with Respect to Ground2.0V to +14.0V ⁽¹⁾ |
| V_{PP} Supply Voltage with Respect to Ground2.0V to +14.0V^{(1)} |

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability

Note: 1. Minimum voltage is -0.6V dc which may undershoot to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is V_{CC} + 0.75V dc which may overshoot to +7.0 volts for pulses of less than 20 ns.

Operating Modes

| Mode \ Pin | CE | ŌE | PGM | Ai | V _{PP} | Outputs |
|---------------------------------------|-----------------|-----------------|------------------|---|------------------|---------------------|
| Read | V _{IL} | V _{IL} | X ⁽¹⁾ | Ai | Х | D _{OUT} |
| Output Disable | Х | V _{IH} | Х | Х | Х | High Z |
| Standby | V _{IH} | Х | Х | Х | X ⁽⁵⁾ | High Z |
| Rapid Program ⁽²⁾ | V _{IL} | V _{IH} | V _{IL} | Ai | V _{PP} | D _{IN} |
| PGM Verify | V _{IL} | V _{IL} | V _{IH} | Ai | V _{PP} | D _{OUT} |
| PGM Inhibit | V _{IH} | Х | Х | х | V _{PP} | High Z |
| Product Identification ⁽⁴⁾ | V _{IL} | V _{IL} | х | $A9 = V_{H}^{(3)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A14 = V_{IL}$ | V _{cc} | Identification Code |

Notes: 1. X can be V_{IL} or V_{IH} .

2. Refer to Programming Characteristics.

3. $V_{H} = 12.0 \pm 0.5 V.$

4. Two identifier bytes may be selected. All Ai inputs are held low (V_{IL}), except A9 which is set to V_H and A0 which is toggled low (V_{IL}) to select the Manufacturer's Identification byte and high (V_{IH}) to select the Device Code byte.

5. Standby V_{CC} current (I_{SB}) is specified with $V_{PP} = V_{CC}$. $V_{CC} > V_{PP}$ will cause a slight increase in I_{SB}.





DC and AC Operating Conditions for Read Operation

| | | | | AT27C516 | | |
|------------------------------|------|--------------|--------------|--------------|--------------|--------------|
| | | -45 | -55 | -70 | -85 | -10 |
| Operating | Com. | 0°C - 70°C |
| Temperature (Case) | Ind. | -40°C - 85°C |
| V _{CC} Power Supply | | $5V\pm10\%$ | 5V ± 10% | 5V ± 10% | 5V ± 10% | $5V\pm10\%$ |

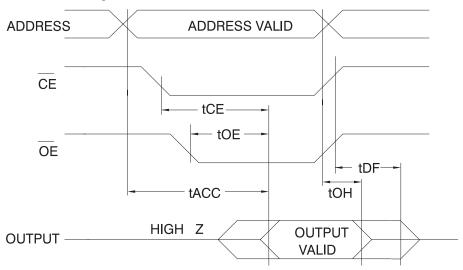
DC and Operating Characteristics for Read Operation

| Symbol | Parameter | Condition | Min | Max | Units |
|---------------------------------|---|---|------|-----------------------|-------|
| ILI | Input Load Current | $V_{IN} = 0V$ to V_{CC} | | ± 1 | μΑ |
| I _{LO} | Output Leakage Current | $V_{OUT} = 0V$ to V_{CC} | | ± 5 | μΑ |
| I _{PP1} ⁽²⁾ | V _{PP} ⁽¹⁾ Read/Standby Current | $V_{PP} = V_{CC}$ | | 10 | μΑ |
| | | I_{SB1} (CMOS), $\overline{CE} = V_{CC \pm} 0.3V$ | | 100 | μΑ |
| I _{SB} | V _{CC} ⁽¹⁾ Standby Current | I_{SB2} (TTL), \overline{CE} = 2.0 to V_{CC} + 0.5V | | 1 | mA |
| I _{cc} | V _{CC} Active Current | $f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA}, \overline{CE} = V_{IL}$ | | 30 | mA |
| V _{IL} | Input Low Voltage | | -0.6 | 0.8 | V |
| V _{IH} | Input High Voltage | | 2.0 | V _{CC} + 0.5 | V |
| V _{OL} | Output Low Voltage | I _{OL} = 2.1 mA | | 0.4 | V |
| V _{OH} | Output High Voltage | I _{OH} = -400 μA | 2.4 | | V |

Notes: 1. V_{CC} must be applied simultaneously with or before V_{PP} and removed simultaneously with or after V_{PP}

2. V_{PP} may be connected directly to V_{CC} , except during programming. The supply current would then be the sum of I_{CC} and I_{PP}

AC Waveforms for Read Operation⁽¹⁾



AC Characteristics for Read Operation

| | | | | AT27C516 | | | | | | | | | |
|-----------------------------------|---|--|-----|----------|-----|-----|-----|-----|-----|-----|-----|-----|-------|
| | | | -4 | 45 | -{ | 55 | -7 | 70 | -8 | 35 | -1 | 0 | |
| Symbol | Parameter | Condition | Min | Мах | Min | Max | Min | Max | Min | Max | Min | Max | Units |
| t _{ACC} ⁽³⁾ | Address to Output Delay | $\overline{CE} = \overline{OE} = V_{IL}$ | | 45 | | 55 | | 70 | | 85 | | 100 | ns |
| t _{CE} ⁽²⁾ | CE to Output Delay | $\overline{OE} = V_{IL}$ | | 45 | | 55 | | 70 | | 85 | | 100 | ns |
| t _{OE} ⁽²⁾⁽³⁾ | OE to Output Delay | $\overline{CE} = V_{IL}$ | | 20 | | 25 | | 25 | | 30 | | 30 | ns |
| t _{DF} ⁽⁴⁾⁽⁵⁾ | OE or CE High to Ou whichever occurred | | | 20 | | 25 | | 25 | | 30 | | 30 | ns |
| t _{OH} | Output Hold from Ad whichever occurred | | 7 | | 7 | | 7 | | 0 | | 0 | | ns |

Notes: 1. Timing measurement reference level is 1.5V for -45 and -55 devices. Input AC drive levels are $V_{IL} = 0.0V$ and $V_{IH} = 3.0V$. Timing measurement reference levels for all other speed grades are $V_{OL} = 0.8V$ and $V_{OH} = 2.0V$. Input AC drive levels are $V_{IL} = 0.45V$ and $V_{IH} = 2.4V$.

2. \overline{OE} may be delayed up to t_{CE} - t_{OE} after the falling edge of \overline{CE} without impact on t_{CE}.

3. OE may be delayed up to t_{ACC} - t_{OE} after the address is valid without impact on t_{ACC}.

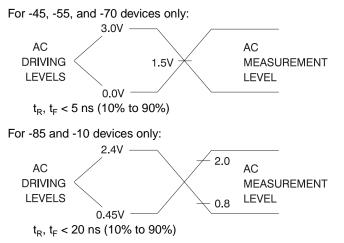
4. This parameter is only sampled and is not 100% tested.

5. Output float is defined as the point when data is no longer driven.

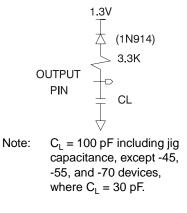




Input Test Waveforms and Measurement Levels



Output Test Load



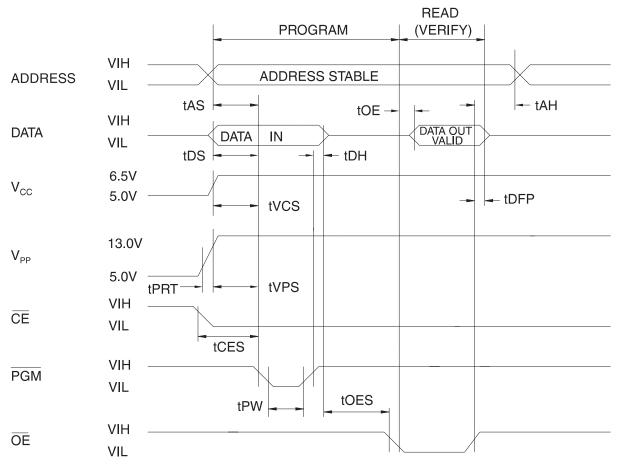
Pin Capacitance

 $f = 1 \text{ MHz}, T = 25^{\circ}C^{(1)}$

| Symbol | Тур | Мах | Units | Conditions |
|------------------|-----|-----|-------|----------------|
| C _{IN} | 4 | 10 | pF | $V_{IN} = 0V$ |
| C _{OUT} | 8 | 12 | pF | $V_{OUT} = 0V$ |

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.

Programming Waveforms⁽¹⁾



Notes: 1. The Input Timing Reference is 0.8V for $\rm V_{IL}$ and 2.0V for $\rm V_{IH}.$

- 2. t_{OE} and t_{DFP} are characteristics of the device but must be accommodated by the programmer.
- 3. When programming the AT27C516 at 0.1 μ F capacitor is required across V_{PP} and ground to suppress spurious voltage transients.

DC Programming Characteristics

 $T_{A} = 25 \pm 5^{\circ}C, \, V_{CC} = 6.5 \pm 0.25 V, \, V_{PP} = 13.0 \pm 0.25 V$

| | | | Li | | |
|------------------|---|---|------|-----------------------|-------|
| Symbol | Parameter | Test Conditions | Min | Max | Units |
| ILI | Input Load Current | $V_{IN} = V_{IL}, V_{IH}$ | | ±10 | μA |
| V _{IL} | Input Low Level | | -0.6 | 0.8 | V |
| V _{IH} | Input High Level | | 2.0 | V _{cc} + 0.1 | V |
| V _{OL} | Output Low Voltage | I _{OL} = 2.1 mA | | 0.4 | V |
| V _{OH} | Output High Voltage | I _{OH} = -400 μA | 2.4 | | V |
| I _{CC2} | V _{CC} Supply Current (Program and Verify) | | | 50 | mA |
| I _{PP2} | V _{PP} Supply Current | $\overline{CE} = \overline{PGM} = V_{IL}$ | | 30 | mA |
| V _{ID} | A9 Product Identification Voltage | | 11.5 | 12.5 | V |





AC Programming Characteristics

 $T_{A} = 25 \pm 5^{\circ}C, \, V_{CC} = 6.5 \pm 0.25V, \, V_{PP} = 13.0 \pm 0.25V$

| | | | Li | imit | | |
|------------------|---|---|------|---------|----|--|
| Symbol | Parameter | Test Conditions ⁽¹⁾ | Min | Min Max | | |
| t _{AS} | Address Setup Time | | 2 | | μs | |
| t _{CES} | CE Setup Time | | 2 | | μs | |
| t _{OES} | OE Setup Time | Input Rise and Fall Times: | 2 | | μs | |
| t _{DS} | Data Setup Time | (10% to 90%) 20 ns | 2 | | μs | |
| t _{AH} | Address Hold Time | Input Pulse Levels: | 0 | | μs | |
| t _{DH} | Data Hold Time | 0.45V to 2.4V | 2 | | μs | |
| t _{DFP} | OE High to Output Float Delay ⁽²⁾ | | 0 | 130 | ns | |
| t _{VPS} | V _{PP} Setup Time | Input Timing Reference Level: 0.8V to 2.0V | 2 | | μs | |
| t _{VCS} | V _{CC} Setup Time | | 2 | | μs | |
| t _{PW} | PGM Program Pulse Width ⁽³⁾ | Output Timing Reference Level: | 47.5 | 52.5 | μs | |
| t _{OE} | Data Valid from OE | 0.8V to 2.0V | | 150 | ns | |
| t _{PRT} | V _{PP} Pulse Rise Time During Programming | | 50 | | ns | |

Notes: 1. V_{CC} must be applied simultaneously or before V_{PP} and removed simultaneously or after V_{PP}

2. This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven—see timing diagram.

3. Program Pulse width tolerance is 50 $\mu sec \pm 5\%.$

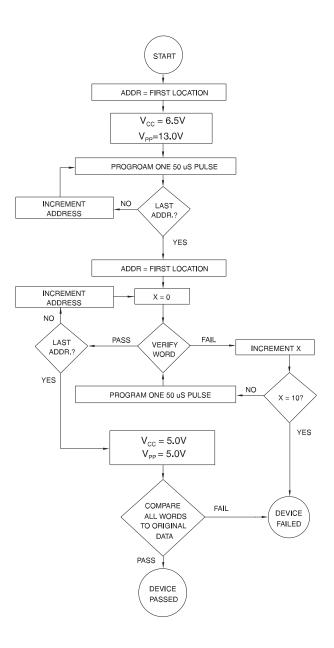
Atmel's 27C516 Integrated Product Identification Code

| | Pins | | | | | | | Hex | | | |
|--------------|------|--------|----|------------|----|------------|------------|-----|----|----|------|
| Codes | A0 | 015-08 | 07 | O 6 | O5 | O 4 | O 3 | 02 | 01 | 00 | Data |
| Manufacturer | 0 | 0 | 0 | 0 | 0 | 1 | 1 | 1 | 1 | 0 | 001E |
| Device Type | 1 | 0 | 1 | 1 | 1 | 1 | 0 | 0 | 1 | 0 | 00F2 |

AT27C516

Rapid Programming Algorithm

A 50 μ s PGM pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and V_{PP} is raised to 13.0V. Each address is first programmed with one 50 μ s PGM pulse without verification. Then a verification / reprogramming loop is executed for each address. In the event a word fails to pass verification, up to 10 successive 50 μ s pulses are applied with a verification after each pulse. If the word fails to verify after 10 pulses have been applied, the part is considered failed. After the word verifies properly, the next address is selected until all have been checked. V_{PP} is then lowered to 5.0V and V_{CC} to 5.0V. All words are read again and compared with the original data to determine if the device passes or fails.





Ordering Information

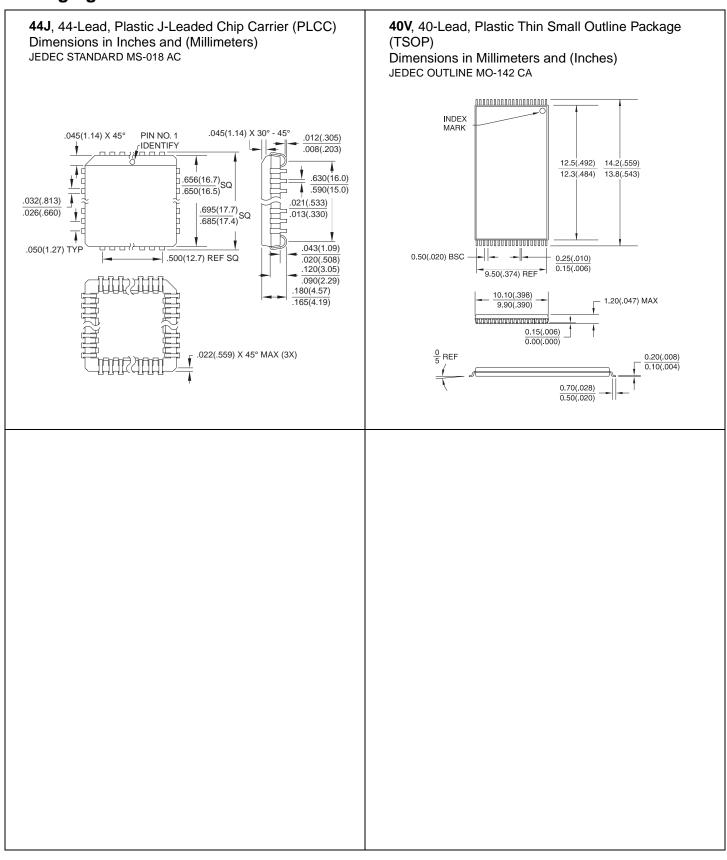
| t _{ACC} I _{CC} (mA) (ns) Active Standby | | (mA) | | | |
|--|--------|---------|---------------|---------|-----------------|
| | | Standby | Ordering Code | Package | Operation Range |
| | 30 0.1 | | AT27C516-45JC | 44J | Commercial |
| 45 | 30 | 0.1 | AT27C516-45VC | 40V | (0°C to 70°C) |
| 40 | 30 | 0.1 | AT27C516-45JI | 44J | Industrial |
| | 30 | 0.1 | AT27C516-45VI | 40V | (-40°C to 85°C) |
| | 30 | 0.1 | AT27C516-55JC | 44J | Commercial |
| 55 | 30 | 0.1 | AT27C516-55VC | 40V | (0°C to 70°C) |
| 55 | 30 | 0.1 | AT27C516-55JI | 44J | Industrial |
| | 30 | 0.1 | AT27C516-55VI | 40V | (-40°C to 85°C) |
| | 30 | 0.1 | AT27C516-70JC | 44J | Commercial |
| 70 | 30 | 0.1 | AT27C516-70VC | 40V | (0°C to 70°C) |
| 70 | 30 | 0.1 | AT27C516-70JI | 44J | Industrial |
| | 30 | 0.1 | AT27C516-70VI | 40V | (-40°C to 85°C) |
| | 30 | 0.1 | AT27C516-85JC | 44J | Commercial |
| 85 | 30 | 0.1 | AT27C516-85VC | 40V | (0°C to 70°C) |
| 65 | 30 | 0.1 | AT27C516-85JI | 44J | Industrial |
| | 30 | 0.1 | AT27C516-85VI | 40V | (-40°C to 85°C) |
| | 30 | 0.1 | AT27C516-10JC | 44J | Commercial |
| 100 | 30 | 0.1 | AT27C516-10VC | 40V | (0°C to 70°C) |
| 100 | 30 | 0.1 | AT27C516-10JI | 44J | Industrial |
| | 30 | 0.1 | AT27C516-10VI | 40V | (-40°C to 85°C) |

| | Package Type | | | | | | |
|-----|---|--|--|--|--|--|--|
| 44J | 44-Lead, Plastic J-Leaded Chip Carrier (PLCC) | | | | | | |
| 40V | | | | | | | |

AT27C516

AT27C516

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